Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	•
10/785,153	ISHIKAWA ET AL.	
Examiner	Art Unit	
Seung H. Lee	2876	

SEARCHED			
Class	Subclass	Date	Examiner
235	376	3/5/2006	SHL
		,	
	-		
	<u>.</u>		

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
Above	3/5/2006	SHL	
	Subclass	Subclass Date	

SEARCH N (INCLUDING SEARC		<b>'</b> )
	DATE	EXMR
235/383, 385 (see printouts)	3/5/2006	SHL
707/1, 101 (see printouts)	3/5/2006	SHL
705/28 (see printouts)	3/5/2006	SHL
PCT citees	3/5/2006	SHL